Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10537001	AKIYAMA ET AL.
Examiner	Art Unit
Shin, Dana	1635

SEARCHED					
Class	Subclass	Date	Examiner		
536	23.1, 24.5	7-21-07, 7-31-07	DS		
514	44	7-21-07, 7-31-07	DS		

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST -updated, search strategy attached.	7-21-07, 7-31- 07	DS		
STIC- SEQ ID NO:1, interference search, results available on SCORE	7-25-07	DS		

INTERFERENCE SEARCH						
Class	Subclas	SS Date	Examiner			
536	23.1, 24.5	7-21-07, 7-31-07	DS			
514	44	7-21-07, 7-31-07	DS			

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